Session Program

13–19 Jun 2015

2015 CAP Congress / Congrès de l'ACP 2015

T2-1 Materials characterization: microscopy, imagining, spectroscopy (DCMMP) / Caractérisation des matériaux: microscopie, imagerie, spectroscopie (DPMCM)

University of Alberta
Edmonton, AB

Tuesday 16 June

13:45

T2-1 Materials characterization: microscopy, imagining, spectroscopy (DCMMP) / Caractérisation des matériaux: microscopie, imagerie, spectroscopie (DPMCM)

Session | **Location:** University of Alberta, NINT Taylor room | **Convener:** Eundeok Mun

13:45–14:15

Ultrafast Transmission Electron Microscopy and its Nanoplasmonic Applications

Speaker

Prof. Aycan Yurtsever

14:15–14:45

Means of mitigating the limits to characterization of radiation sensitive samples in an electron microscope.

Speaker

Marek Malac

14:45–15:00

Terahertz Scanning Tunneling Microscopy in Ultrahigh Vacuum

Speaker

Mr Vedran Jelic

15:00–15:15

Identifying differences in long-range structural disorder in solids using mid-infrared spectroscopy

Speaker

Ben Xu

15:15